

PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G8 SMD CRYSTAL
SPEC. NO. (P/N)	G83270021
CUSTOMER P/N	
ISSUE DATE	Jun.16,2016
VERSION	A

APPROVED	PREPARED	QA
<i>Brenda</i>	<i>Clair</i>	<i>Song Yang</i>
APPROVED BY CUSTOMER :		AVL Status
Please return one copy with approval to PSE-TW		

PSE Technology Corporation

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*RoHS Compliant

*** A company of  **PERICOM Semiconductor Corporation** ***

TYPE G8 SMD CRYSTAL

G83270021

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VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
01	Jun.1,2016			New	
02	Jun.2,2016			1. Updated Temperature Coefficient & C0 2. Added Reliability	
03	Jun.15,2016			Updated Shunt Capacitance & Motional Capacitance	
A	Jun.16,2016			Release formal version	



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ELECTRICAL SPECIFICATIONS

SRe Part Number : G83270021

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 20	ppm	at 25 °C ± 5 °C
Load Capacitance	CL	12.5	pF	Typ.
Drive Level	DL	0.1 / 0.5	µW	Typ. / Max.
Equivalent Series Resistance	ESR	70	KΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C ²	± 0.01ppm/°C ²
Operating Temperature Range	TR	-40 to 85	°C	
Shunt Capacitance	C0	1.5	pF	Typ.
Motional Capacitance	C1	6.5	fF	Typ.
Quality Factor	Q	13	K	Min.
Aging		± 3	ppm	Max. 1st year
Storage Temperature Range		-40 to 85	°C	
Insulation Resistance		500	MΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	<ul style="list-style-type: none">• Without mechanical damage such as breaks and satisfy sealing specification.• Frequency change: Within ±5ppm• Equivalent series resistance(E.S.R) change: Within 5kΩ
2	Shear test	Apply 20N(2.04kgf) static load to the core of quartz crystal units in the direction of the arrow using a R0.5 scratch tool, then hold for 5 seconds.	
3	Core body strength	Apply 10N(1.02kgf) static load to the quartz crystal units center in the direction of the arrow using a R0.5 pushing tool, then hold for 10 seconds.	
4	Vibration	Frequency sweep method shall be applied as follows. Quartz crystal units shall be vibrated with the sweeping frequency from 10Hz to 55Hz and return to 10Hz in 1 minute, with 1.5mm amplitude. This vibration shall be applied for 2 hours in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-6.	
5	Shock	Quartz crystal units shall be accelerated at 9810m/s ² by 1ms pulse duration. This shock shall be applied 3 times in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-27.	

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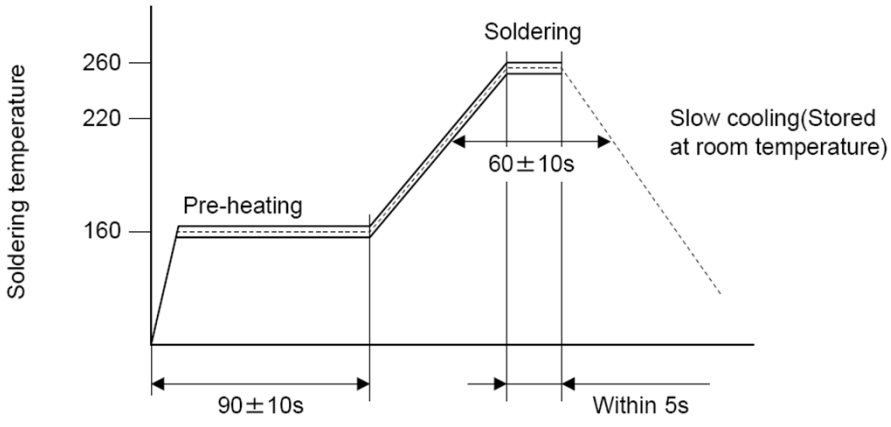
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6	Cold	Quartz crystal units shall be stored in the $-40\pm 3^{\circ}\text{C}$ atmosphere for 1000 hours. Other procedures conform to JIS C 60068-2-1.	<ul style="list-style-type: none"> • Frequency change: Within $\pm 5\text{ppm}$ • Equivalent series resistance(E.S.R) change: Within $5\text{k}\Omega$ 														
7	Dry heat	Quartz crystal units shall be stored in the $100\pm 2^{\circ}\text{C}$ atmosphere for 100 hours. Other procedures conform to JIS C 60068-2-2.	<ul style="list-style-type: none"> • After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. 														
8	Damp heat	Quartz crystal units shall be stored in the $40\pm 2^{\circ}\text{C}$ atmosphere with 90 to 95% relative humidity for 1000 hours. Other procedures conform to JIS C 60068-2-3.															
9	Change of temperature	Quartz crystal units shall be subjected successively 100 cycles of temperature change shown below. Other procedures conform to JIS C 0025.															
		<table border="1"> <thead> <tr> <th></th> <th>Temperature</th> <th>Duration</th> </tr> </thead> <tbody> <tr> <td>1</td> <td>$-40\pm 3^{\circ}\text{C}$</td> <td>30min.</td> </tr> <tr> <td>2</td> <td>Normal temperature</td> <td>Within 30 sec.</td> </tr> <tr> <td>3</td> <td>$100\pm 2^{\circ}\text{C}$</td> <td>30min.</td> </tr> <tr> <td>4</td> <td>Normal temperature</td> <td>Within 30 sec.</td> </tr> </tbody> </table>			Temperature	Duration	1	$-40\pm 3^{\circ}\text{C}$	30min.	2	Normal temperature	Within 30 sec.	3	$100\pm 2^{\circ}\text{C}$	30min.	4	Normal temperature
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4	Normal temperature	Within 30 sec.															
10	Sealing	Both the test methods specified below shall be applied.															
		Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes.	<ul style="list-style-type: none"> • Without repetitive leaking bubbles from quartz crystal units. 														
		Quartz crystal units shall be tested by Mass spectrometric leakage detector to measure the leakage rate of helium gas.	<ul style="list-style-type: none"> • $1\times 10^{-9}\text{ Pa}\cdot\text{m}^3/\text{s}$ or less 														
11	Aging	Quartz crystal units shall be stored in the $85\pm 3^{\circ}\text{C}$ atmosphere for 720 ± 12 hours.	<ul style="list-style-type: none"> • Frequency change: Within $\pm 5\text{ppm}$ • Equivalent series resistance(E.S.R) change: Within $5\text{k}\Omega$ • After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. 														
12	Solder-ability	Terminals coated with flux shall be immersed in the solder bath for 3.5 ± 0.5 seconds.	<ul style="list-style-type: none"> • Minimum 95% of immersed terminal shall be covered with new uniform solder. 														
		<table border="1"> <thead> <tr> <th></th> <th>Items</th> <th>Conditions</th> </tr> </thead> <tbody> <tr> <td>1</td> <td>Solder</td> <td>Sn-3.0Ag-0.5Cu</td> </tr> <tr> <td>2</td> <td>Flux</td> <td>Approximately 25wt% methanol(JIS K 8891) solution of resin(JIS K 5902).</td> </tr> <tr> <td>3</td> <td>Solder temperature</td> <td>$245\pm 5^{\circ}\text{C}$</td> </tr> </tbody> </table>			Items	Conditions	1	Solder	Sn-3.0Ag-0.5Cu	2	Flux	Approximately 25wt% methanol(JIS K 8891) solution of resin(JIS K 5902).	3	Solder temperature	$245\pm 5^{\circ}\text{C}$		
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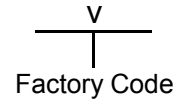
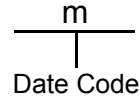
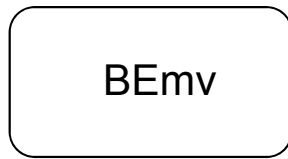
13	Resistance to soldering heat	<p>Reflow soldering method</p> <p style="text-align: center;">Temperature profile</p>  <p>Peak temperature: $260\pm 5^{\circ}\text{C}$ for within 5seconds. Soldering temperature: 220°C or higher for 60 ± 10 seconds. Pre-heating temperature: $160\pm 10^{\circ}\text{C}$ for 90 ± 10 seconds. Quartz crystal units which is put on PCB shall be through reflow soldering furnace twice with the condition shown above.</p>	<ul style="list-style-type: none"> • Frequency change: Within $\pm 5\text{ppm}$ • Equivalent series resistance (E.S.R) change: Within $10\text{k}\Omega$ • After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. • Without distinct deformation in appearance.
		<p>Hot Air method</p> <p>Apply hot air for 7 ± 0.5seconds, distance 10mm, $300\pm 5^{\circ}\text{C}$, flow 10L/minutes</p>	<ul style="list-style-type: none"> • Frequency change: Within $\pm 5\text{ppm}$ • Equivalent series resistance(E.S.R) change: Within $5\text{k}\Omega$ • After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. • Without distinct deformation in appearance.
14	Solubility to resistance	<p>Soak cleaning</p> <p>Quartz crystal units shall be soaked in isopropyl alcohol at normal temperature for 90 seconds.</p>	<ul style="list-style-type: none"> • Without mechanical damage such as breaks and satisfy sealing specification. • Frequency change: Within $\pm 5\text{ppm}$ • Equivalent series resistance(E.S.R) change: Within $5\text{k}\Omega$ • Without distinct deformation in appearance. • Marking shall be legible.

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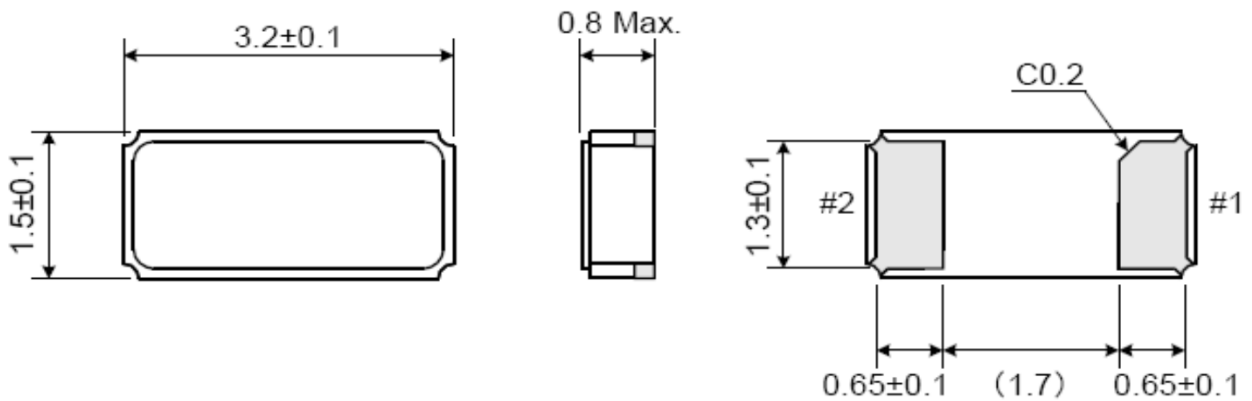
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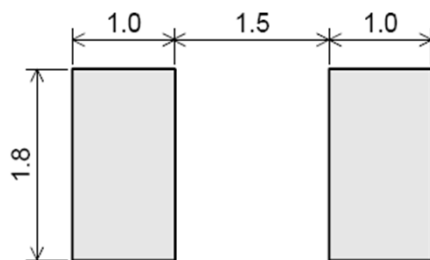
Marking



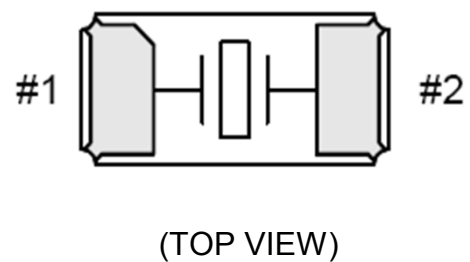
Dimensions (Units: mm)



Recommended Soldering Pattern



Internal connection



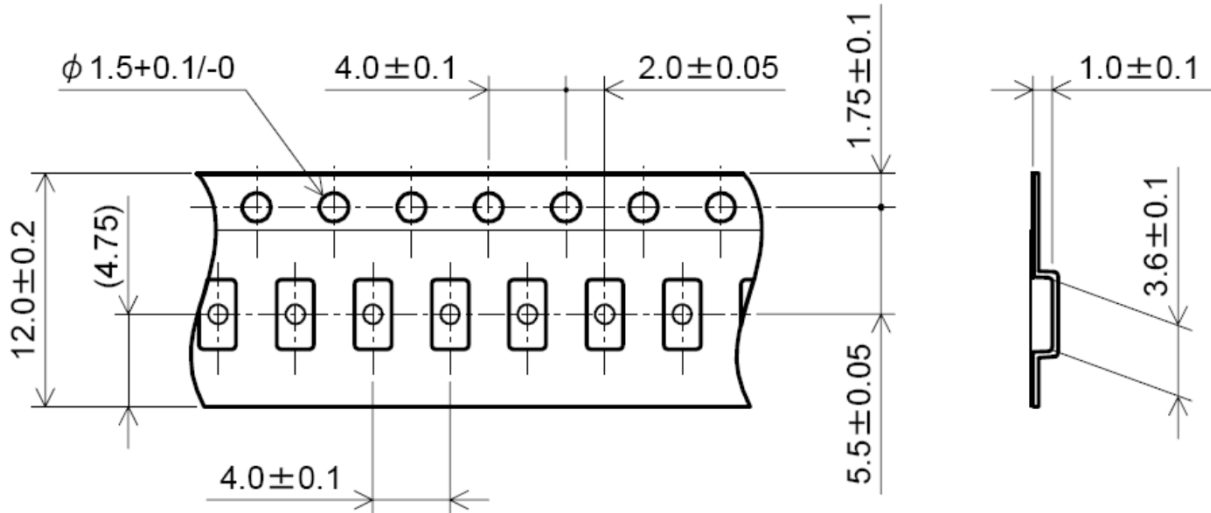
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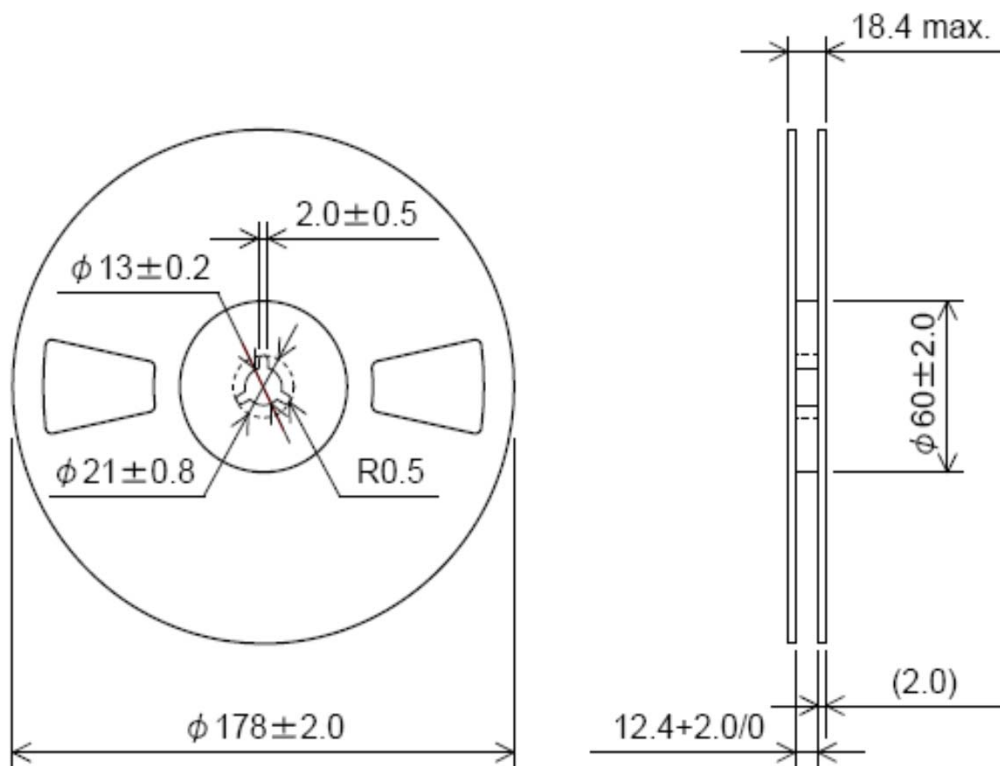
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TAPING (Units: mm)



REEL (Units: mm)



Quantity : 3000pcs / Reel

单击下面可查看定价，库存，交付和生命周期等信息

[>>Diodes Incorporated\(达尔科技\)](#)